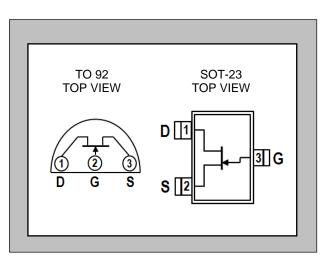
LINEAR SYSTEMS

Twenty-Five Years Of Quality Through Innovation

FEATURES					
ULTRA LOW NOISE	$e_n = 1.8 V / \sqrt{Hz}$				
LOW INPUT CAPACITANCE	$C_{ISS} = 4pF$				
ABSOLUTE MAXIMUM RATINGS ¹ @ 25 °C (unless otherwise stated)					
Maximum Temperatures					
Storage Temperature	-55 to +150°C				
Junction Operating Temperature	-55 to +150°C				
Maximum Power Dissipation					
Continuous Power Dissipation TA=25°C	300mW ⁴				
Maximum Currents					
Gate Forward Current	$I_{G(F)} = 10 \text{mA}$				
Maximum Voltages					
Gate to Source	$V_{GSO} = 60V$				
Gate to Drain	$V_{GDO} = 60V$				

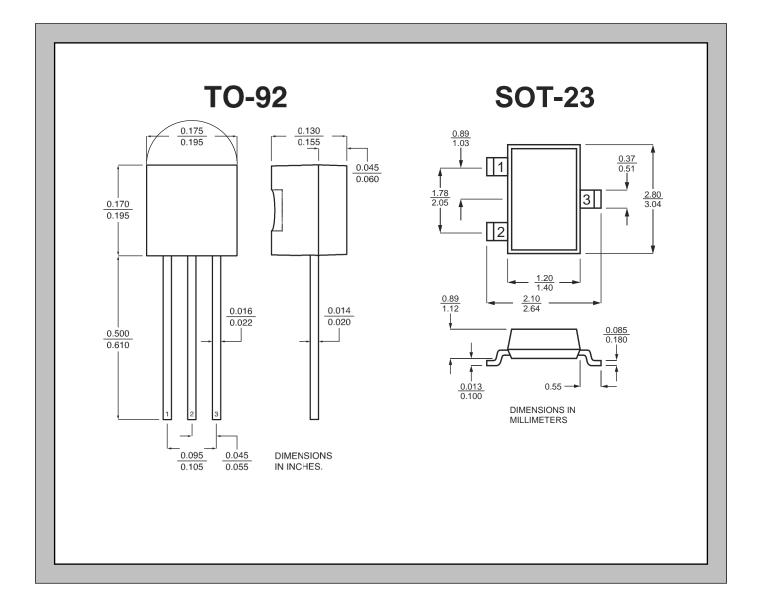
LSK189

LOW NOISE, LOW CAPACITANCE SINGLE N-CHANNEL JFET



* For equivalent monolithic dual, see LSK489

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS	
BV _{GSS}	Gate to Source Breakdown Voltage	-60			V	$V_{DS} = 0, I_{D} = -1nA$	
V _{GS(OFF)}	Gate to Source Pinch-off Voltage	-1.5		-3.5	V	$V_{DS} = 15V, I_D = 1nA$	
V _{GS}	Gate to Source Operating Voltage	-0.5		-3.5	V	$V_{DS} = 15V, I_D = 500\mu A$	
I _{DSS} ²	Drain to Source Saturation Current	2.5	5	15	mA	$V_{DS} = 15V, V_{GS} = 0$	
l _G	Coto Operating Current		-2	-25	pА	$V_{DG} = 15V, I_D = 200\mu A$	
I _G	Gate Operating Current		-0.8	-10	nA	TA=125°C	
I _{GSS}	Gate to Source Leakage Current			-100	pА	V _{GS} = -15V	
G _{fs}	Full Conductance Transconductance	1500			μS	$V_{DS} = 15V, V_{GS} = 0, f = 1kHz$	
		1000	1500		μS	$V_{DS} = 15V, I_D = 500\mu A$	
G _{OS}	Full Output Conductance			40	μS	$V_{DS} = 15V, V_{GS} = 0$	
Gos	Output Conductance		1.8	2.7	μS	$V_{DS} = 15V, I_D = 200\mu A$	
NF	Noise Figure			0.5	dB	$V_{DS} = 15V, V_{GS} = 0, R_G = 10M\Omega, f = 100Hz, NBW = 6Hz$	
en	Noise Voltage		1.8	2.0	nV/√Hz	$V_{DS} = 15V$, $I_D = 2mA$, $f = 1kHz$, NBW = 1Hz	
en	Noise Voltage		2.8	3.5	nV/√Hz	$V_{DS} = 15V$, $I_D = 2mA$, $f = 10Hz$, NBW = 1Hz	
CISS	Common Source Input Capacitance		4	8	pF		
C _{RSS}	Common Source Reverse Transfer Cap.			3	pF	$V_{DS} = 15V, I_D = 500\mu A, f = 1MHz$	



1. Absolute maximum ratings are limiting values above which serviceability may be impaired.

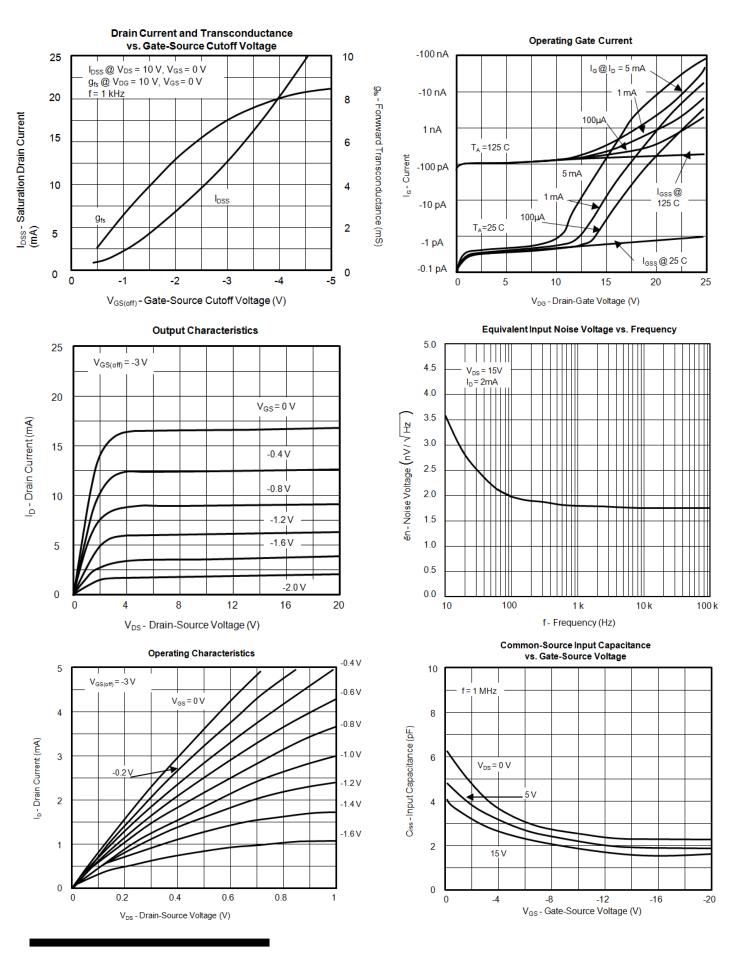
2. Pulse Test: PW \leq 300µs, Duty Cycle \leq 3%.

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3. All characteristics MIN/TYP/MAX numbers are absolute values. Negative values indicate electrical polarity only.

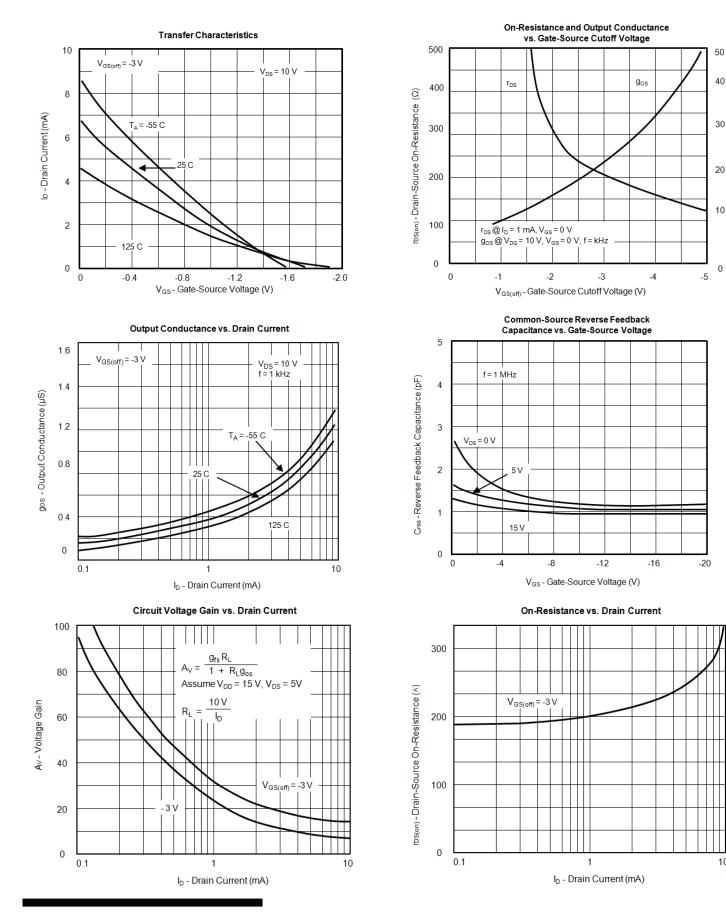
4. Derate 2.8 mW °C above 25°C.

Typical Characteristics



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Typical Characteristics (Cont'd)

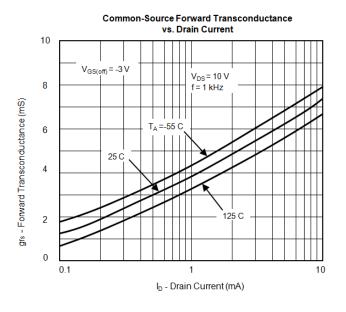


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gos - Output Conductance (µS)

10

Typical Characteristics (Cont'd)



Linear Integrated Systems (LIS) is a 25-year-old, third-generation precision semiconductor company providing high-quality discrete components. Expertise brought to LIS is based on processes and products developed at Amelco, Union Carbide, Intersil and Micro Power Systems by company President John H. Hall. Hall, a protégé of Silicon Valley legend Dr. Jean Hoerni, was the director of IC Development at Union Carbide, co-founder and vice president of R&D at Intersil, and founder/president of Micro Power Systems.

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